

SHEET 1 OF 4

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Substitute for form 1449/PTO)

ATTY. DOCKET NO.

044117-0143

SERIAL NO.

10/539,771

APPLICANT

Eric PINET, et al.

FILING DATE

January 10, 2006

GROUP

1797**U.S. PATENT DOCUMENTS**

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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/Samuel Siefke/

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